FORM PTO-1449	SERIAL NO.		CASE NO.
		To be Assigned	9281-4610
LIST OF PATENTS AND PUBLICATIONS FOR	FILING DATE		GROUP ART UNIT
APPLICANT'S INFORMATION DISCLOSURE		Herewith	
STATEMENT			
(use several sheets if necessary)	APPLICANT:	Mitsuru Kano et	al.

REFERENCE DESIGNATION
U.S. PATENT DOCUMENTS

EXAMINER INITIAL NUMBER DATE NAME SUBCLASS DATE

OUT OF THE PROPERTY OF THE PROPE

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANS YES	LATION NO
Ø	A1	Japanese Unexamined Patent Application Publication No. 2002-311449	10/2002	Japan		X	
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EXAMINER INITIAL	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



10/627,890 CASE NO. 9281-4610 GROUP ART UNIT

2871

LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT

(use several sheets if necessary)

APPLICANT(S): Mitsuru Kano et al.

July 24, 2003

SERIAL NO.

FILING DATE

REFERENCE	DESIG	GNATION	U.S. PATE	NT DOCUMENTS		
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
A	B1	6,342,935 B1	01/2002	Yong-Kyu Jang et al.		
K)	B2	6,219,119 B1	04/2001	Yutaka Nakai		
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FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANS	LATION NO
K3	В3	EP 0 867 747 A2	09/1998	EPO		X	
N	B4	EP 1 174 735 A2	01/2002	EPO		X	
A3	B5	EP 0 536 898 A	04/1993	EPO		X	

EXAMINER INITIAL		OTHER ART (including Author, Title, Date, Pertinent Pages, etc.)
AT	B6	FULLY SELF-ALIGNED TRI-LAYER ALPHA-SI:H THIN-FILM TRANSISTORS WITH DEPOSITED DOPED CONTACT LAYER, Thomasson D.B. et al, IEEE Electron Device Letters, IEEE, Inc., Vol. 19, no. 4, (4/1/1998) Pages 124-126
N	B7	INFLUENCE OF CURRENT-VOLTAGE CHARACTERISTICS ON IMAGE-STICKING OF THIN-FILM DIODE LIQUID-CRYSTAL DISPLAYS, Hirai T. et al, Japanese Journal of Applied Physics, Publication Office Japanese Journal of Applied Physics., Tokyo, Japan, Vol. 38, no. 9A, Part 1, (09/1999), Pages 5287-5291

EXAMINER Andrew	Elutto	DATE CONSIDERED	10/14/04	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

	TRANSMITTAL LET	TER	Case No. 9281-4610
Serial No. 10/627,890	Filing Date July 24, 2003	Examiner To be Assigned.	Group Art Unit 2871